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Dwyer 7-15

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Patent Application

Applicants(s): Dwyer et al.

Case:

7-15

Assistant Commissioner of Patents

Washington, D.C. 20231

Serial No.:

09/975,762

Filing Date: Group:

October 9, 2001 2185

Examiner:

Unassigned

Title:

Method and Apparatus for Reducing Cache Thrashing

RECEIVED

INFORMATION DISCLOSURE STATEMENT

APR 0,3 2002

Technology Center 2100

Sir:

Pursuant to 37 C.F.R. §§1.56, 1.97 and 1.98, Applicant's attorney wishes to bring to the attention of the Patent and Trademark Office the following document listed on the accompanying PTO Form 1449. A copy of the listed item is enclosed.

- 1. Kaxiras et al, "Cache Decay: Exploiting Generational Behavior to Reduce Cache Leakage Power," IEEE, (2001).
- 2. Lai et al., "Dead-Block Prediction & Dead-Block Correlating Prefetchers," IEEE, (2001).
- 3. Mendelson et al, "Modeling Live and Dead Lines in Cache Memory System," IEEE, Trans. on Computers, v. 42, no. 1, (January 1993).

The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made, or as an admission that the information cited is considered to be material to patentability or that no other material information exists.

Respectfully submitted,

Kein M. Masa

Date: March 27, 2002

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FORM PTO-1449 (MODIF

LIST OF PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT



Applicant: Dwye

Case: Serial No.: 09/975,762

Filing Date: October 9, 2001

2185

Group:

			U.S. PATENT DOCU	MENTS	
EXAMINER				·	FILING DATE
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Examiner

Applicant.

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to